

Search Notes

Application/Control No.

10/717,033

Examiner

Christopher M. Keehan

Applicant(s)/Patent under
Reexamination

ELAU ET AL.

Art Unit

1712

SEARCHED

Class	Subclass	Date	Examiner
528	32		
	10		
	125		
	127		
	170		
	205		
	220		
	397		
	401		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
same as	above	4/14/2005	CMK

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	4/14/2005	CMK
Inventor name search		
10/005584, 09/619237, and STN structure searched therewith		